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09/851,313 05/09/2001		5/09/2001	Tatsuya Usami	NEC01P069-MSb	2820
21254	7590	06/15/2004		EXAMINER	
MCGINN & 8321 OLD C	,		MALDONADO, JULIO J		
SUITE 200	OURINO	OSE ROND	ART UNIT	PAPER NUMBER	
VIENNA, V	A 22182-	3817	2823		

DATE MAILED: 06/15/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)				
		09/851,313	USAMI, TATSUYA				
Office Action Sun	nmary	Examin r	Art Unit				
		Julio J. Maldonado	2823				
The MAILING DATE of thi Period for Reply	s communication app	ears on the cover sheet with the c	orrespondence address				
<ul> <li>If NO period for reply is specified above, th</li> <li>Failure to reply within the set or extended period</li> </ul>	COMMUNICATION. the provisions of 37 CFR 1.13 te of this communication. s than thirty (30) days, a reply e maximum statutory period w heriod for reply will, by statute, three months after the mailing		nely filed s will be considered timely. the mailing date of this communication. D (35 U.S.C. § 133).				
Status							
1) Responsive to communication	ation(s) filed on 03 Ju	ne 2004.	•				
2a)⊠ This action is <b>FINAL</b> .		action is non-final.					
<i>'</i> —	closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
Disposition of Claims							
4) Claim(s) 1,2,4-6,8 and 31-46 is/are pending in the application.  4a) Of the above claim(s) is/are withdrawn from consideration.							
_		wi irom consideration.					
/ <u> </u>	☐ Claim(s) 1,2,4-6,8 and 31-46 is/are rejected.						
8) Claim(s) are subject		election requirement.					
Application Papers							
9\ The specification is objects	ed to by the Examine	•					
9) The specification is objected to by the Examiner.  10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.							
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).							
	Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).						
	1) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.						
Priority under 35 U.S.C. § 119							
	of a claim for foreign	priority under 35 H S C & 119/a	)_(d) or (f)				
12)⊠ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).  a)⊠ All b)□ Some * c)□ None of:							
1.⊠ Certified copies of the priority documents have been received.							
2. Certified copies of t	ne priority documents	have been received in Applicati	on No				
<ol><li>Copies of the certification</li></ol>	ed copies of the prior	ity documents have been receive	ed in this National Stage				
application from the	International Bureau	(PCT Rule 17.2(a)).					
* See the attached detailed C	Office action for a list of	of the certified copies not receive	ed.				
Attachment(s)							
<ol> <li>Notice of References Cited (PTO-892)</li> <li>Dotice of Draftsperson's Patent Drawir</li> </ol>	na Review (PTO-948)	4)					
3) 🔲 Information Disclosure Statement(s) (F		5) Notice of Informal F	Patent Application (PTO-152)				
Paper No(s)/Mail Date		6) 🔲 Other:					

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#### **DETAILED ACTION**

- 1. The final rejection as set forth in paper mailed on 05/24/2003 is withdrawn in view of applicants' amendments.
- 2. A new rejection is included in the application.
- 3. Claims 1, 2, 4-6, 8 and 31-46 are pending in the present application.

### Claim Rejections - 35 USC § 102

4. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 5. Claims 1, 2, 4-6, 8, 31, 34, 37, 41, 42 and 44 are rejected under 35 U.S.C. 102(e) as being anticipated by Lou (U.S. 6,277,732 B1).

In reference to claims 1, 4, 5, 8, 41 and 42, Lou (Figs.1A, 1B, 1D and 1E) teaches damascene interconnect including a multilayered insulation film, wherein said multilayered insulation film comprises a first insulation layer (208) comprising an organic material having a dielectric constant which is lower than a silicon oxide dielectric constant; a second insulation layer (210) comprising a polysiloxane compound having an Si-H group and formed on and adhering to a top of said first insulation layer (208); a third insulation layer (212) made of silicon oxide and formed on and adhering to a top of said second insulation layer (210); and a conductive wire (216, 218) embedded in a

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groove formed in said multi-layered insulation film, said multi-layered insulation film being disposed between said wire (216, 218), wherein said second insulation layer (210) comprises a hydride organosiloxane (column 3, line 5 – column 4, line 60).

Although Lou does not expressly disclose forming a plurality of grooves, this feature is seen to be inherent because the interconnection structure of Fig.1E would have multiple vias as the interconnection structure is continuously showing.

In reference to claims 2 and 6, Lou teaches wherein said first insulation layer comprises spin on glass materials such as aromatic-containing organic resins (column 3, lines 43 – 45).

In reference to claim 31, Lou teaches wherein said dielectric constant of said first insulation layer is no greater than 3.5 (column 4, lines 43 – 45).

In reference to claim 34, Lou teaches wherein said first insulation layer comprises a thickness greater than a thickness of said second insulation layer; and wherein said first insulation layer comprises a thickness greater than a thickness of said third insulation layer (Fig.1D).

In reference to claim 37, Lou teaches wherein a bottom of said groove is formed on a same surface as said first insulation layer (Fig.1E).

In reference to claim 44, Lou teaches wherein a surface of said multi-layered film is substantially coplanar with a surface of said plurality of wires (Fig.1E).

## Claim Rejections - 35 USC § 103

6. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

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(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

7. Claims 32 and 36 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lou (U.S. 6,277,732 B1) as applied to claims 1, 2, 4-6, 8, 31, 34, 37, 41, 42 and 44 above, and further in view of The Applicants Admitted Prior Art.

Lou substantially teaches all aspects of the invention including a first dielectric layer comprised of spin on glass (SOG) materials, but fails to disclose wherein said SOG are organopolysiloxane including methyl silsesquioxane (MSQ). However, the prior art teaches using SOG materials as dielectric layer, wherein said SOG materials include methyl silsesquioxane (Instant page 5, lines 9-24). Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to combine the teachings of Lou and the prior art to substitute the SOG material taught by Lou for the SOG material disclosed by the prior art because art recognized suitability for an intended purpose has been recognized to be motivation to combine (MPEP 2144.07), and furthermore, because using MSQ reduces crosstalk between metal wires (Instant page 2, lines 12-15).

8. Claim 33 is rejected under 35 U.S.C. 103(a) as being unpatentable over Lou (U.S. 6,277,732 B1) as applied to claims 1, 2, 4-6, 8, 31, 34, 37, 41, 42 and 44 above, and further in view of Aoi (U.S. 6,333,257 B1).

Lou teaches all aspects of the invention including a first dielectric layer selected form a material including fluorinated polyimide but fail to teach using first insulation layer comprising polyaryl ether. However, Aoi (Figs.4a-11c) teaches a multilayered insulation

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film having wiring embedded therein, wherein interlayer insulation layer (204) comprises any arbitrary material such as fluorinated polyimide and polyaryl ether (column 10, lines 1 – 11). It would have been within the scope of one of ordinary skill in the art to combine the teachings of Lou and Aoi to enable using the dielectric materials of Aoi in Lou because one of ordinary skill in the art at the time the invention was made would have been led to the conclusion that the selection of known materials based on its suitability for its intended use supported a prima facie obviousness. MPEP 2144.07.

9. Claim 35 is rejected under 35 U.S.C. 103(a) as being unpatentable over Lou (U.S. 6,277,732 B1) as applied to claims 1, 2, 4-6, 8, 31, 34, 37, 41, 42 and 44 above, and further in view of Yau et al. (U.S. 6,072,227).

Lou teaches a multilayered insulation film including an adhesive layer (210) between two interlayer dielectrics (208, 212) but fails to disclose wherein said adhesive layer comprises a first layer and a second layer placed in said first layer. However, You et al. (Figs.8H and 10H) teach a damascene structure comprising a multilayered insulation film, wherein said multilayered insulation film comprises a first dielectric layer (710) that can be made of an organic material having a dielectric constant which is lower than a silicon oxide dielectric constant (column 14, lines 10 – 14); a second dielectric layer (714, 716, 718) comprising an oxidized organic silane layer (column 14, lines 20 – 22); and a third dielectric layer (722) that can be made of an inorganic material (column 13, lines 9 – 13), wherein said adhesive layer comprises a first layer (714) and a second layer (718) placed in said first layer, wherein said first (714) and said second (718) layer are made from the same material (column 13, line 9 – column

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14, line 59). It would have been within the scope of one of ordinary skill in the art to combine the teachings of Lou and Yau et al. to enable the second dielectric layer of Lou to be comprised of more than one layer according to the teachings of Yau et al. because it is prima facie obvious to combine two compositions each of which is taught by the prior art to be useful for the same purpose, in order to form a third composition to be used for the very same purpose (MPEP 2144.06).

10. Claims 39, 40, 45 and 46 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lou (U.S. 6,277,732 B1) as applied to claims 1, 2, 4-6, 8, 31, 34, 37, 41, 42 and 44 above, and further in view of Allada et al. (U.S. 6,218,317 B1) and Wolf et al. (Silicon Processing for the VLSI Era, Volume 1) alone or in combination with Chen et al. (Effects of slurry formulations on chemical-mechanical polishing of low dielectric constant polysiloxanes: hydrido-organo siloxane and methyl silsesquioxane).

Lou teaches a second insulation comprising hydrogen silsesquioxane and methyl silsesquioxane, but fails to teach using a methylated hydrogen silsesquioxane film (MHSQ) at a thickness of about 50nm, wherein said dielectric layer includes repeating units of  $(SiCH_3O_2)_n$ ,  $(SiO_2H)_n$  and  $(SiO_3)_n$ , wherein a molar ratio of  $(SiO_2H)_n$  to a total of said repeating units is at least 0.2, and wherein said dielectric layer is deposited by plasma CVD. However, Allada et al. (Figs.1a-1b) in a related art to the formation of an interconnect structure teach a second insulating film comprising a methylated hydrido organo siloxane polymer (HOSP), wherein said polymer can be formed by spin coating processes or by conventional CVD processes (column 2, lines 7 – 67).

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Furthermore, according to Chen (Fig.1), methylated hydrido organo siloxane polymer (HOSP) includes repeating units of  $(SiCH_3O_2)_n$ ,  $(SiO_2H)_n$  and  $(SiO_3)_n$ , wherein a molar ratio of  $(SiO_2H)_n$  to a total of said repeating units is at least 0.2.

Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention was made to use the insulating layer as taught by Allada et al. in the interconnect formation structure of Lu et al., since this dielectric layers exhibit low dielectric constants (Allada et al., column 2, lines 36-48).

Still, the combined structure of Lou and Allada fail to teach the dielectric layer having a thickness of about 50nm. Notwithstanding, it would have been an obvious matter of design choice bounded by well known manufacturing constraints and ascertainable by routine experimentation and optimization to choose these particular dimensions because applicant has not disclosed that the dimensions are for a particular unobvious purpose, produce an unexpected result, or are otherwise critical, and it appears prima facie that the process would possess utility using another dimension. Indeed, it has been held that mere dimensional limitations are prima facie obvious absent a disclosure that the limitations are for a particular unobvious purpose, produce an unexpected result, or are otherwise critical. See, for example, In re Rose, 220 F.2d. 459, 105 USPQ 237 (CCPA 1955); In re Rinehart, 531 F.2d 1048, 189 USPQ 143 (CCPA 1976); Gardner v. TEC Systems, Inc., 725 F.2d 1338, 220 USPQ 777 (Fed. Cir. 1984), cert. denied, 469 U.S. 830, 225 USPQ 232 (1984); In re Dailey, 357 F.2d 669, 149 USPQ 47 (CCPA 1966).

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Furtherstill, the combined teachings of Lou and Allada et al. fail to teach wherein said conventional CVD processes include plasma CVD. However, according to Wolf et al., conventional CVD processes known in the art includes low pressure CVD and plasma CVD (pages 168 – 174). It would have been within the scope of one of ordinary skill in the art to combine the teachings of Lou and Allada et al. with the teachings of Wolf et al. to enable the deposition step of Lou and Allada et al. to be performed according to the teachings of Wolf et al. because one of ordinary skill in the art at the time the invention was made would have been motivated to look to alternative suitable methods of performing the disclosed deposition step of Lou and Allada et al. and art recognized suitability for an intended purpose has been recognized to be motivation to combine. MPEP 2144.07.

11. Claim 43 is rejected under 35 U.S.C. 103(a) as being unpatentable over Lou (U.S. 6,277,732 B1) as applied to claims 1, 2, 4-6, 8, 31, 34, 37, 41, 42 and 44 above, and further in view of Lu et al. (U.S. 6,008,540).

Lou substantially teaches all aspects of the invention but fails to disclose wherein said first insulation layer, said second insulation layer and said third insulation layer of said multi-layered insulation film comprise substantially uniform widths. However, Lu et al. (Figs.2b and 3f) teach an interconnect structure comprising a multi-layered insulation film formed on a semiconductor substrate (102), said multi-layered insulation film comprising a first insulation layer comprising an organic material (342, and column 1, lines 24 – 33) having a dielectric constant which is lower than a silicon oxide dielectric constant; a second insulation layer (344) comprising a polysiloxane compound having

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an Si-H group and formed on and adhering to a top of said first insulation layer (342); a third insulation layer (346) comprising an inorganic material and formed on and adhering to a top of said second insulation layer (344); and a plurality of wires embedded in a groove formed in said multi-layered insulation film, said multi-layered insulation film being disposed between said wires, said first insulation layer, said second insulation layer and said third insulation layer of said multi-layered insulation film comprise either uniform or non-uniform widths (column 3, line 48 – column 6, line 62).

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to combine the teachings of Lou and Lu et al. to enable the dielectric layers of Lou to be configured according to the teachings of Lu et al. because it would be a matter of choice which a person of ordinary skill in the art would have found obvious absent persuasive evidence that a particular configuration was significant. MPEP 2144.04, IV, B.

### Response to Arguments

12. Applicant's arguments with respect to claims 1, 2, 4-6, 8 and 31-46 have been considered but are most in view of the new ground(s) of rejection.

### Conclusion

13. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

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A shortened statutory period for reply to this final action is set to expire THREE

MONTHS from the mailing date of this action. In the event a first reply is filed within

TWO MONTHS of the mailing date of this final action and the advisory action is not

mailed until after the end of the THREE-MONTH shortened statutory period, then the

shortened statutory period will expire on the date the advisory action is mailed, and any

extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of

the advisory action. In no event, however, will the statutory period for reply expire later

than SIX MONTHS from the date of this final action.

14. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to examiner Julio J. Maldonado whose telephone number

is (571) 272-1864. The examiner can normally be reached on Monday through Friday.

15. If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Olik Chaudhuri, can be reached on (571) 272-1855. The fax number for this

group is 703-872-9306 for before final submissions, 703-872-9306 for after final

submissions and the customer service number for group 2800 is (703) 306-3329.

Updates can be found at http://www.uspto.gov/web/info/2800.htm.

Julio J. Maldonado Patent Examiner

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Julio J. Maldonado June 11, 2004

> George Fourson ' Primary Examiner